Abstract of the Disclosure

In a method of forming a film, the supply of a

10 reaction gas is started at a first flow rate into a
chamber in which a plasma is formed, such that an
initial film is formed on a wafer. Then, the supply
of the reaction gas is started at a second flow rate
into the chamber in which the plasma is formed, such

15 that the film is formed on the initial film, the first
flow rate being smaller than the second flow rate.